Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/666,317	MUI ET AL.	
Examiner	Art Unit	
Eria B. Chan	1765	

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Class	Subclass	Date	Examiner
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INT	TERFERENCE SEARCHED		
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SEARCH NOT (INCLUDING SEARCH		,
	DATE	EXMR
Inventor search (UPDATED)	10/19/2005	EC
EAST (all databases) (UPDATED) - see search history printout	10/19/2005	EC
438/5,9,14,16,714,719-721,723,724, 740,743,744; 430/5; 216/60,67,79 (text search only) (UPDATED)	10/19/2005	EC
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